



[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) | [Purchase History](#) | [Go](#)

Welcome United States Patent and Trademark Office

[AbstractPlus](#)

[BROWSE](#)

[SEARCH](#)

[IEEE XPLORE GUIDE](#)

[View Search Results](#)



Access this document



Full Text: PDF (837 KB)

Download this citation

Choose

[Citation & Abstract](#)

Download ASCII Text

[Learn More](#)

Rights and Permissions

[Learn More](#)

Using densely recorded scenes for place recognition

Tat-Jun Chin, Hanlin Goh, Joo-Hwee Lim,

Institute for Infocomm Research, 21 Heng Mui Keng Terrace, 119613 Singapore

This paper appears in: Acoustics, Speech and Signal Processing, 2008. ICASSP 2008 Conference on

Publication Date: March 31 2008-April 4 2008

On page(s): 2101 - 2104

Number of Pages: 2101 - 2104

Location: Las Vegas, NV, USA

ISSN: 1520-6149

ISBN: 978-1-4244-1483-3

Digital Object Identifier: 10.1109/ICASSP.2008.4518056

Date Published in Issue: 2008-05-12 10:48:09.0

Abstract

We investigate the task of efficiently modeling a scene to build a robust place recognition approach which involves densely capturing a place with video recordings to greedily capture viewpoints of the place as possible. Our contribution is a framework to (1) effectively exploit continuity intrinsic in the video sequences to reduce the amount of data to process without visual information which describes a place, and (2) train discriminative classifiers with the place recognition. We show that our method is more efficient and effective than straightforward scene or object category recognition methods on the video frames.

Index Terms

Inspection

Controlled Indexing

Not Available

Non-controlled Indexing

Not Available

Author Keywords

[Pattern recognition](#) [image recognition](#) [image sequence analysis](#) [machine vision](#)

References

No references available on IEEE Xplore.

Citing Documents

No citing documents available on IEEE Xplore.

[View Search Results](#)

[Help](#) | [Contact Us](#) | [Privacy](#)

Indexed by



© Copyright 2008 IEEE